

EPC2105 – Enhancement-Mode GaN Power Transistor Half Bridge Preliminary Specification Sheet

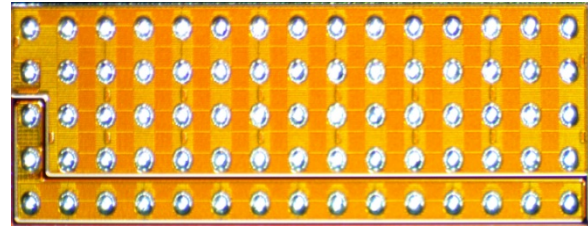
Status: Engineering

Features:

- 97% System Efficiency at 22 A
 - o 48 V_{IN} to 12 V_{OUT}, 300 kHz
 - o Includes output filter
- High Frequency Operation (Beyond 10 MHz)
- High Density Footprint
- Low Inductance Package
- Pb-Free (RoHS Compliant), Halogen Free

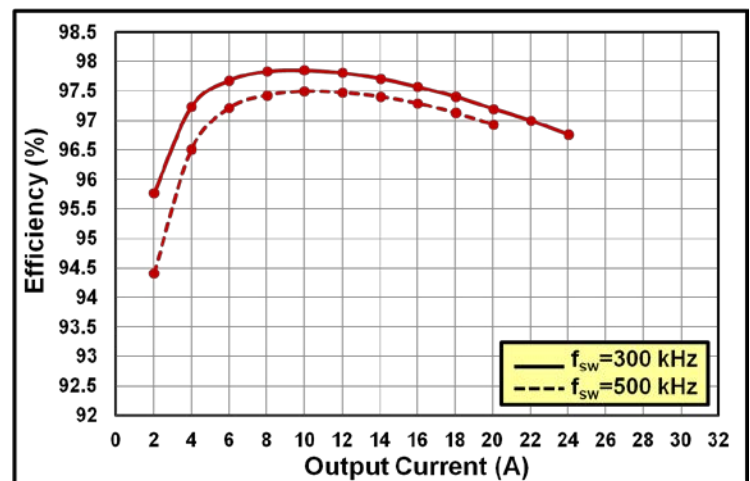
Applications:

- High Frequency DC-DC Conversion



EPC2105 devices are supplied only in passivated die form with solder bumps
Die Size: 6.05 mm x 2.3 mm

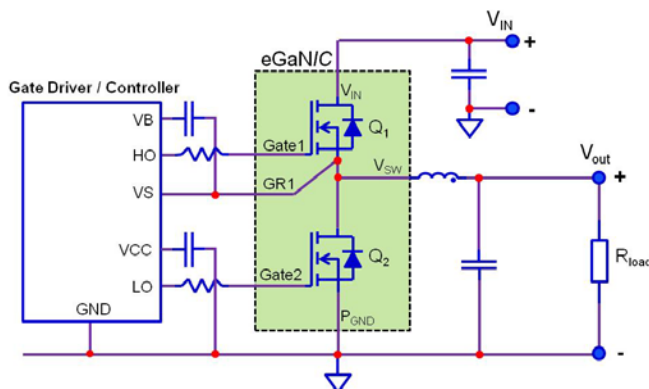
Typical System Efficiency



V_{IN}=48 V V_{OUT}=12 V

Additional application details in [AN018: GaN Integration for Higher DC-DC Efficiency and Power Density](#)

Typical Circuit



MAXIMUM RATINGS

Parameter		Value
Maximum Drain – Source Voltage (V _{SW} to P _{GND} , V _{IN} to V _{SW})		80 V
Maximum Gate – Source Voltage Range (Gate 1 to V _{SW} , Gate 2 to P _{GND})		-4 V < V _{GS} < 6 V
Continuous Drain Current, 25 °C, θ _{JA} = 50 (Q1), 13 (Q2)	Q1 Control FET	9.5 A
	Q2 Sync FET	38 A
Maximum Pulsed Drain Current, 25 °C, T _{pulse} = 300 μs	Q1 Control FET	75 A
	Q2 Sync FET	320 A
Optimum Temperature Range		-40 °C < T _J < 150 °C

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STATIC CHARACTERISTICS

Parameter	Conditions	Q1 Control FET	Q2 Sync FET
Maximum Drain – Source Voltage (BV_{DSS})	Q1: $V_{GS} = 0\text{ V}$, $I_D = 200\text{ }\mu\text{A}$	80 V	
	Q2: $V_{GS} = 0\text{ V}$, $I_D = 700\text{ }\mu\text{A}$		
Maximum Drain – Source Leakage	$V_{DS} = 48\text{ V}$, $V_{GS} = 0\text{ V}$	150 μA	550 μA
Maximum $R_{DS(on)}$	$V_{GS} = 5\text{ V}$, $I_D = 20\text{ A}$	14.5 m Ω	3.4 m Ω
Typical $R_{DS(on)}$	$V_{GS} = 5\text{ V}$, $I_D = 20\text{ A}$	10 m Ω	2.3 m Ω
Gate – Source Threshold Voltage	Q1: $I_D = 2.5\text{ mA}$, $V_{DS} = V_{GS}$	0.8 V < $V_{GS(TH)} < 2.5\text{ V}$	
	Q2: $I_D = 10\text{ mA}$, $V_{DS} = V_{GS}$		
Gate – Source Maximum Positive Leakage	$V_{GS} = 5\text{ V}$	2.5 mA	9 mA
Gate – Source Maximum Negative Leakage	$V_{GS} = -4\text{ V}$	-150 μA	-550 μA

$T_J = 25\text{ }^\circ\text{C}$ unless otherwise stated

DYNAMIC CHARACTERISTICS

Parameter	Conditions	Typical Value		
		Q1 Control FET	Q2 Sync FET	Unit
C_{iss} (Input Capacitance)	$V_{DS} = 40\text{ V}$, $V_{GS} = 0\text{ V}$	0.3	1.1	nF
C_{oss} (Output Capacitance)		0.2	0.8	
C_{rss} (Reverse Transfer Capacitance)		0.003	0.012	
Q_G (Total Gate Charge)	$V_{DS} = 40\text{ V}$, $I_D = 20\text{ A}$, $V_{GS} = 5\text{ V}$	2.5	10	nC
Q_{GS} (Gate to Source Charge)	$V_{DS} = 40\text{ V}$, $I_D = 20\text{ A}$	1	3.2	
Q_{GD} (Gate to Drain Charge)		0.5	2	
$Q_{G(TH)}$ (Gate Charge at Threshold)		0.6	2.4	
Q_{oss} (Output Charge)	$V_{DS} = 40\text{ V}$, $V_{GS} = 0\text{ V}$	11	55	
Q_{RR} (Source-Drain Recovery Charge)		0	0	

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THERMAL CHARACTERISTICS

		TYP		
		Q1 Control FET	Q2 Sync FET	
R _{θJC}	Thermal Resistance, Junction to Case	0.4		°C/W
R _{θJB}	Thermal Resistance, Junction to Board (Note 2)	1.8	1.2	°C/W
R _{θ12}	Thermal Resistance, Cross-Coupling	0.85		°C/W
R _{θJA}	Thermal Resistance, Junction to Ambient (Note 1)	42		°C/W

Note 1: R_{θJA} is determined with the device mounted on one square inch of copper pad, single layer 2 oz copper on FR4 board.

Note 2: ΔT is determined by the following matrix equation:

$$\begin{pmatrix} \Delta T_{Q1} \\ \Delta T_{Q2} \end{pmatrix} = \begin{bmatrix} 1.2 & 0.85 \\ 0.85 & 1.8 \end{bmatrix} \cdot \begin{pmatrix} P_{Q1} \\ P_{Q2} \end{pmatrix}$$

This matrix equation lets you calculate the temperature rise of each FET, given the power dissipated in each FET.

Thermal models for EPC devices available at <http://epc-co.com/epc/DesignSupport/DeviceModels.aspx>

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Figure 1a: EPC2105-Q1 Typical Output Characteristics at 25°C

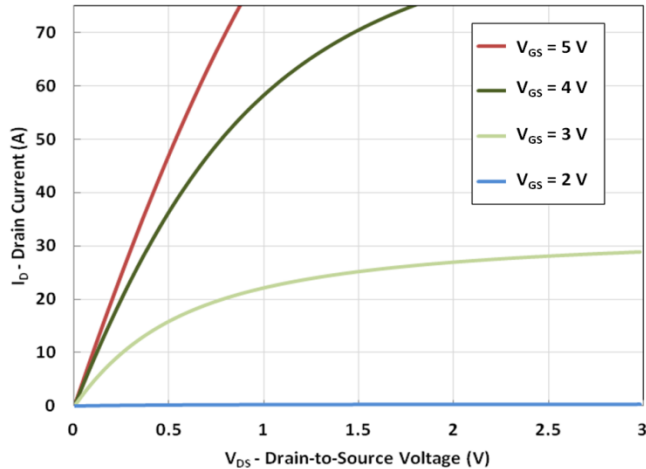


Figure 1b: EPC2105-Q2 Typical Output Characteristics at 25°C

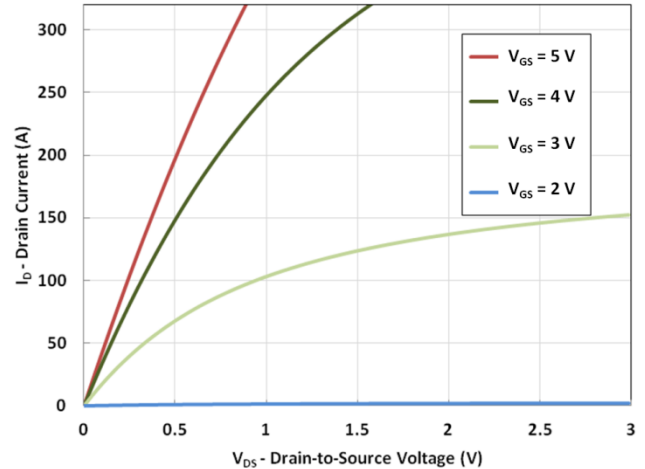


Figure 2a: EPC2105-Q1 Transfer Characteristics

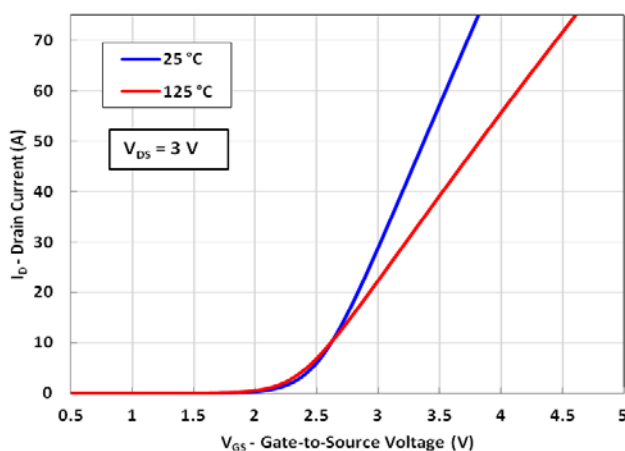


Figure 2b: EPC2105-Q2 Transfer Characteristics

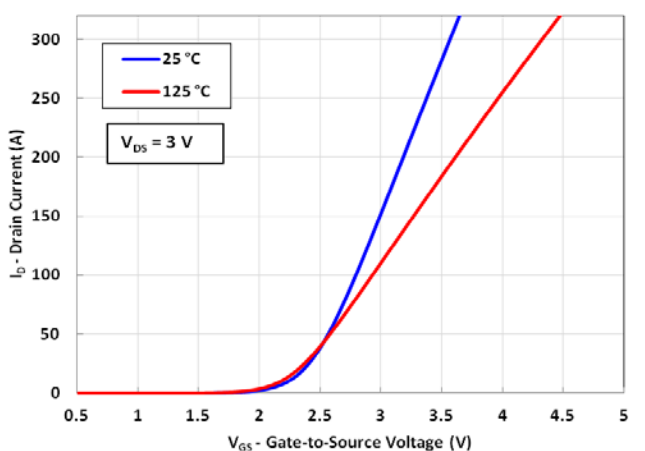


Figure 3a: EPC2105-Q1: $R_{DS(on)}$ vs. V_{GS} for Various Drain Currents

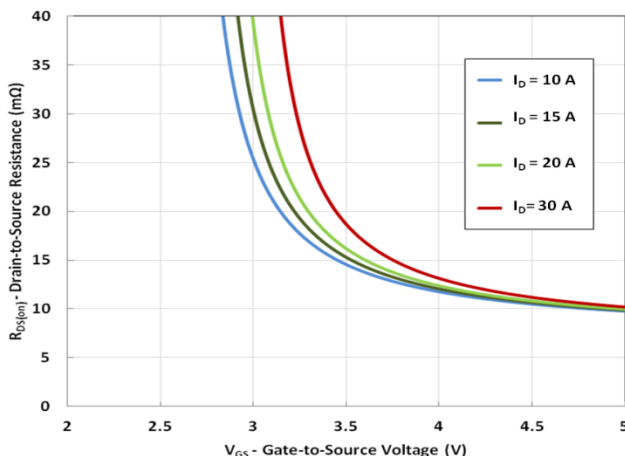
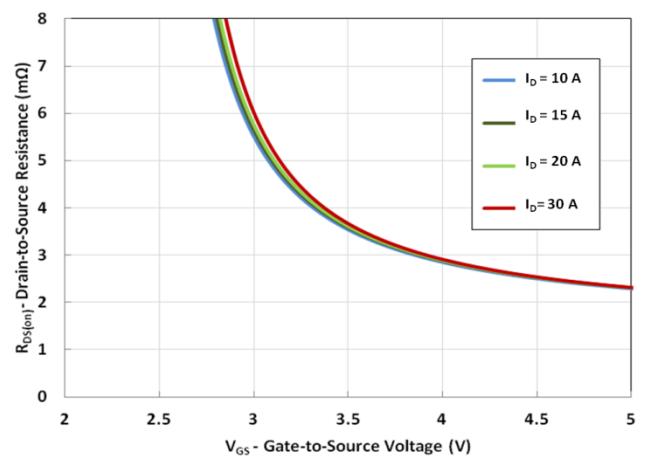


Figure 3b: EPC2105-Q2: $R_{DS(on)}$ vs. V_{GS} for Various Drain Currents



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Figure 4a: EPC2105-Q1: $R_{DS(on)}$ vs. V_{GS} for Various Temperatures

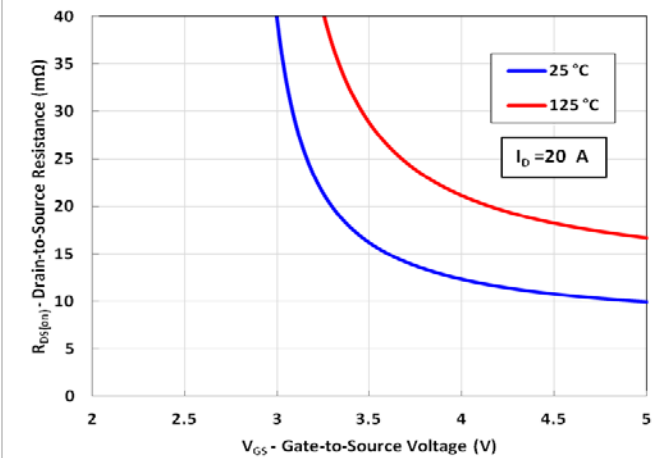


Figure 4b: EPC2105-Q2: $R_{DS(on)}$ vs. V_{GS} for Various Temperatures

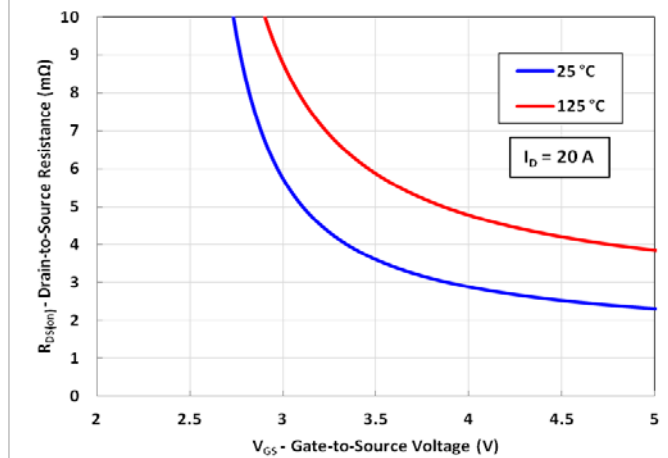


Figure 5a: EPC2105-Q1: Capacitance (Linear Scale)

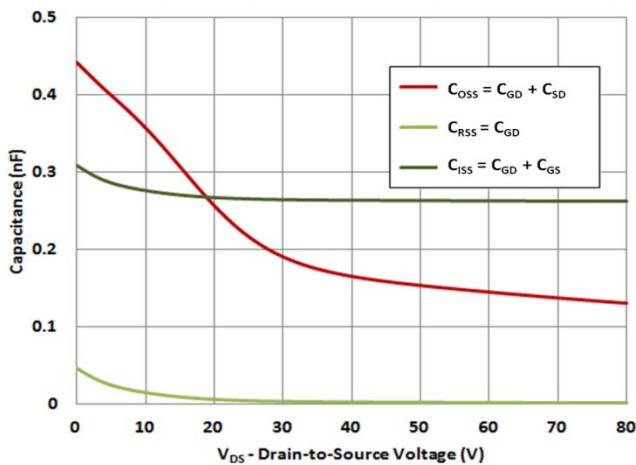


Figure 5b: EPC2105-Q2: Capacitance (Linear Scale)

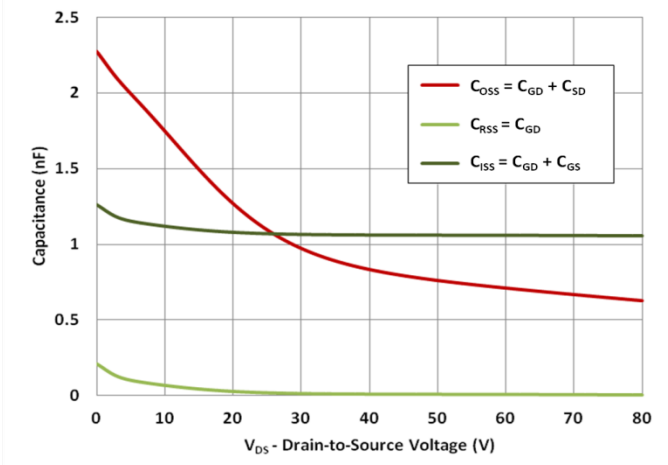


Figure 5c: EPC2105-Q1: Capacitance (Log Scale)

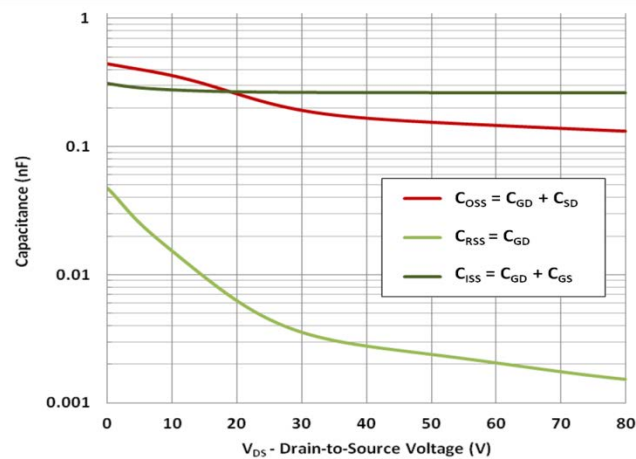
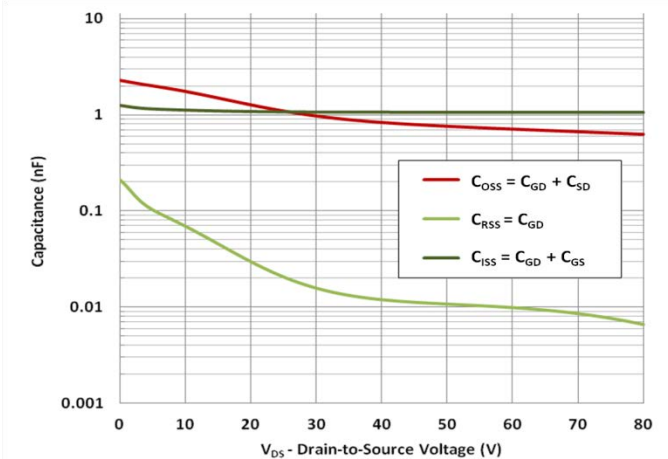


Figure 5d: EPC2105-Q2: Capacitance (Log Scale)



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Figure 6a: EPC2105-Q1: Gate Charge

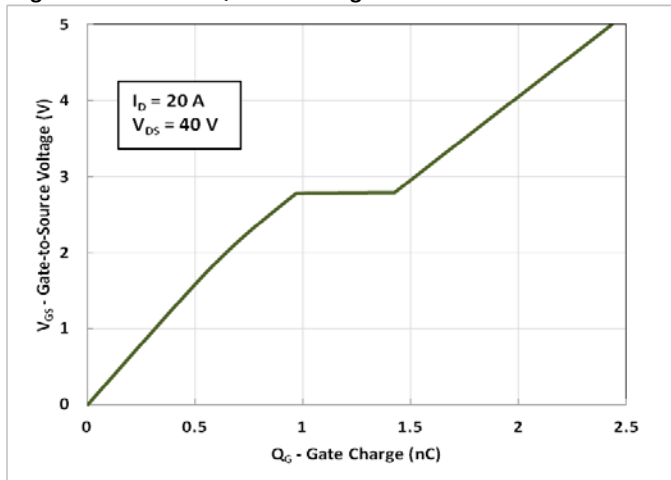


Figure 6b: EPC2105-Q2: Gate Charge

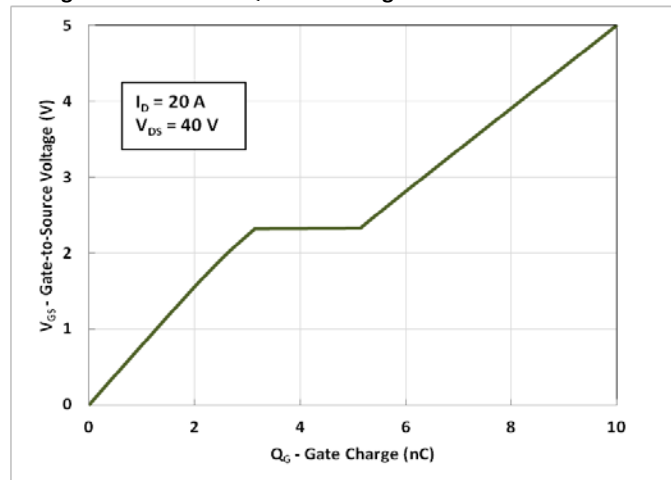


Figure 7a: EPC2105-Q1: Reverse Drain-Source Characteristics

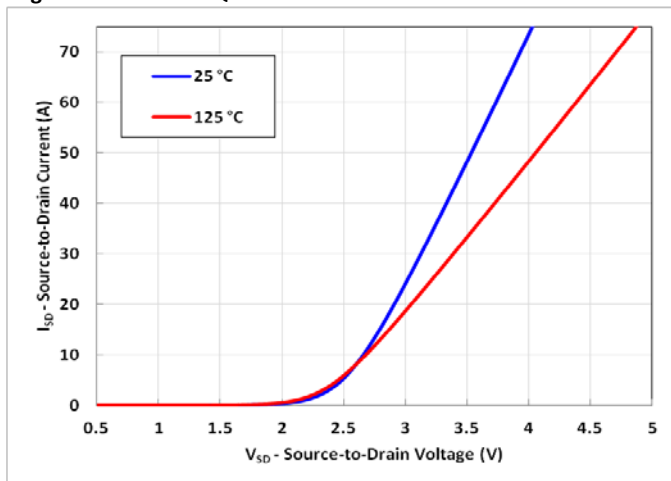


Figure 7b: EPC2105-Q2: Reverse Drain-Source Characteristics

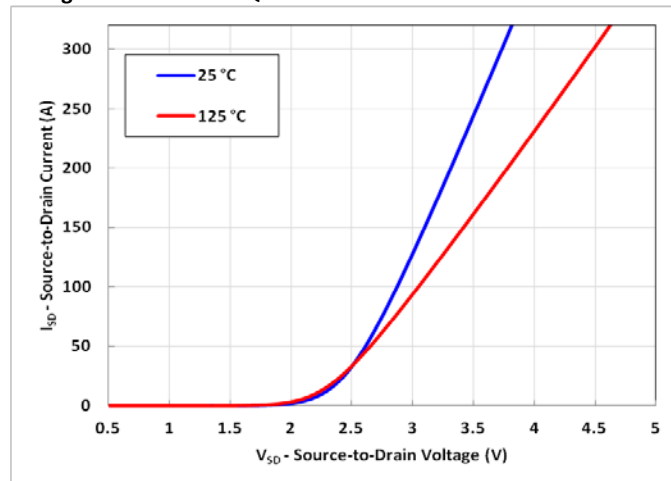


Figure 8a: EPC2105-Q1: Normalized On Resistance vs. Temperature

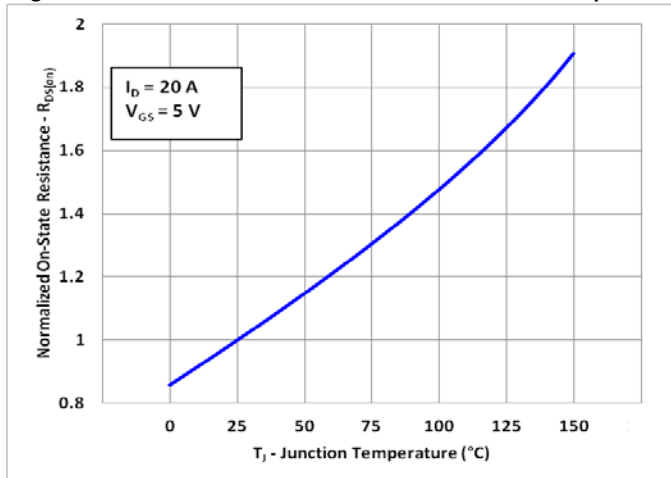
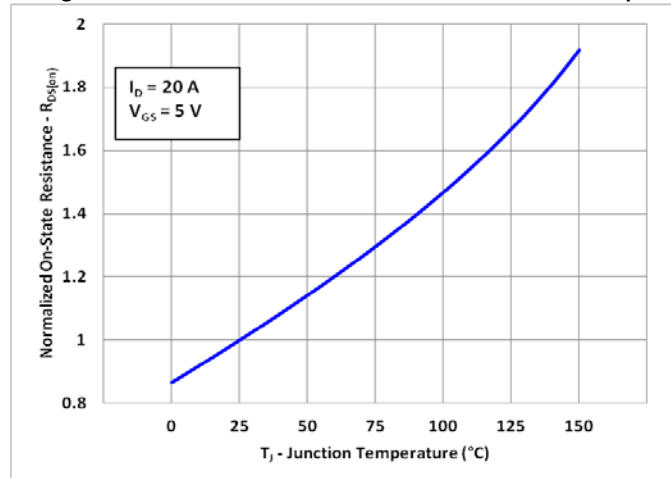


Figure 8b: EPC2105-Q2: Normalized On Resistance vs. Temperature



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Figure 9a:

EPC2105-Q1: Normalized Threshold Voltage vs. Temperature

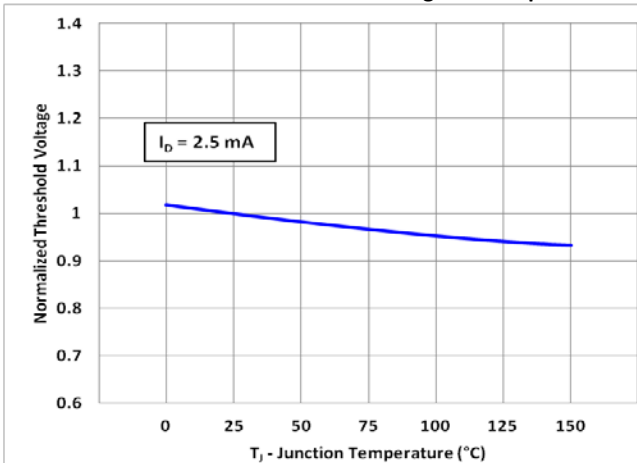
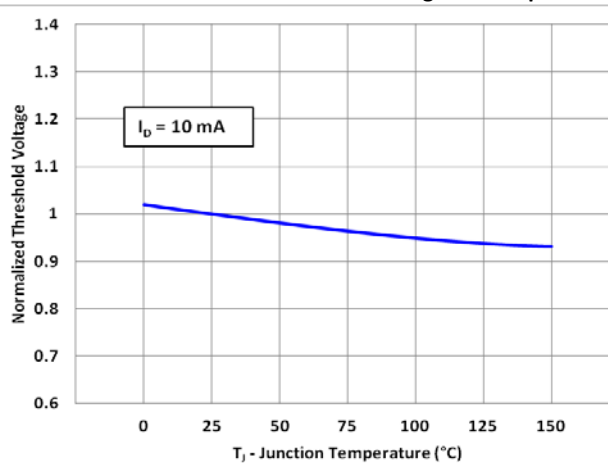


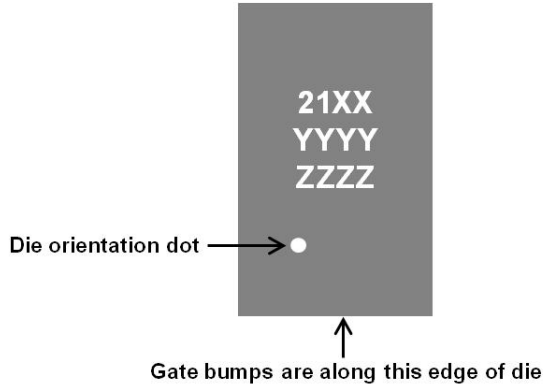
Figure 9b:

EPC2105-Q2: Normalized Threshold Voltage vs. Temperature



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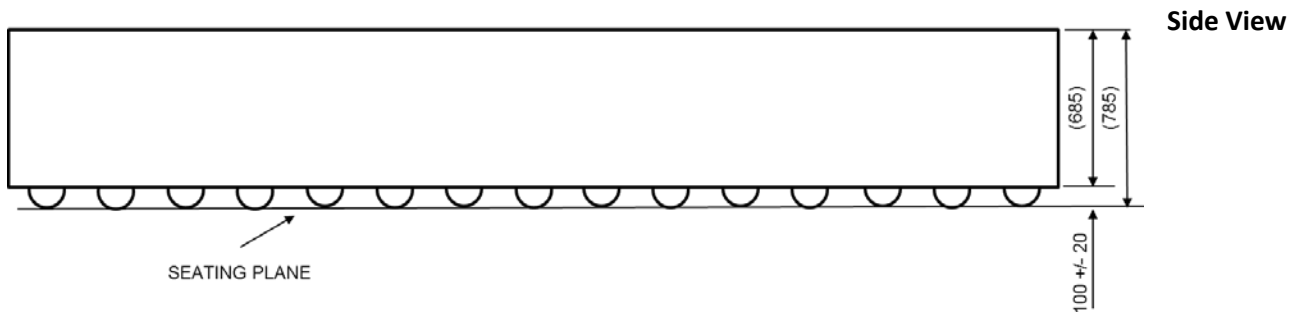
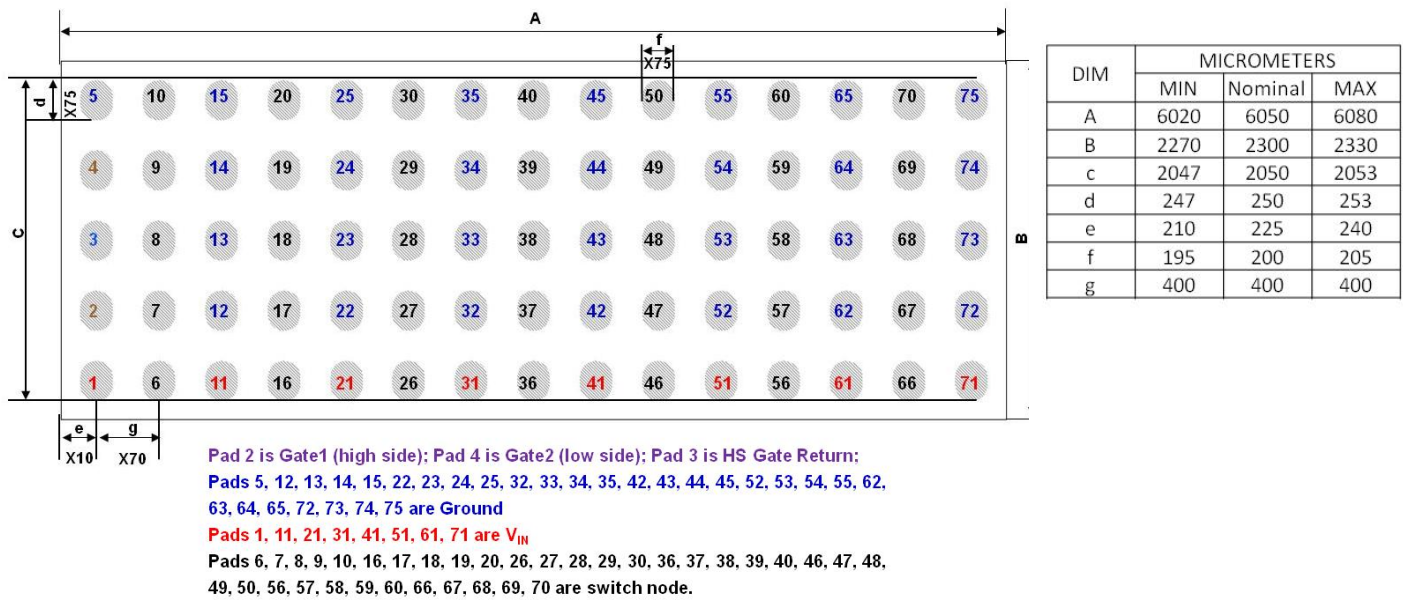
DIE MARKINGS



Part Number	Laser Marking		
	Part # Marking Line 1	Lot_Date Code Marking Line 2	Lot_Date Code Marking Line 3
EPC2105ENGR	21XX	YYYY	ZZZZ

DIE OUTLINE

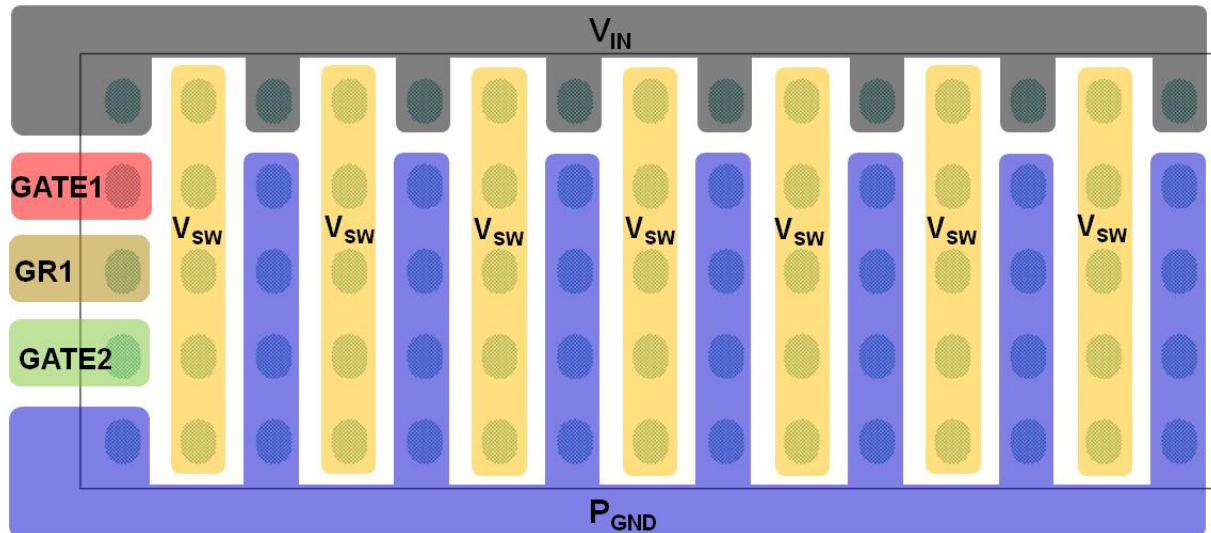
Solder Bar View



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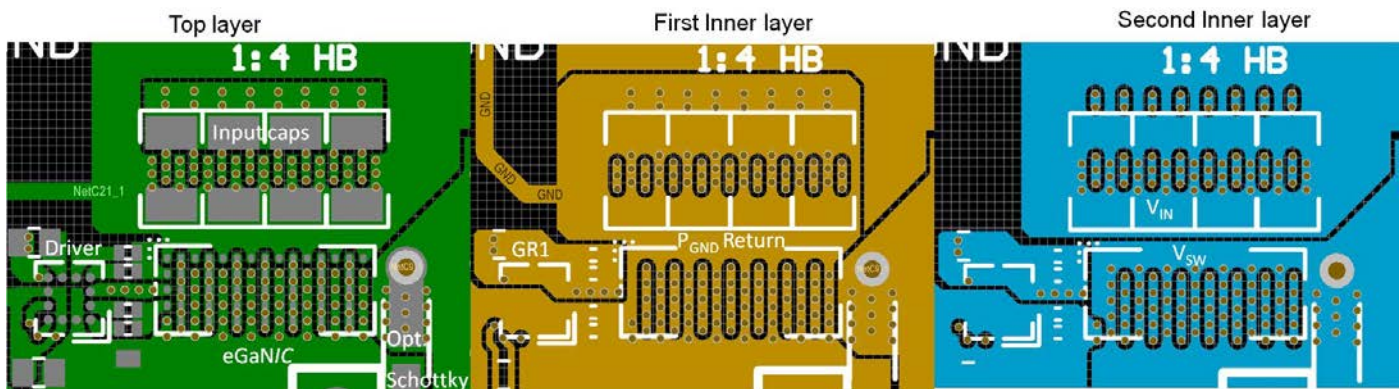
RECOMMENDED LAND PATTERN

(Units in μm)



Land pattern is solder mask defined.

LAYOUT EXAMPLE



Recommended PCB Layout

Gerber Files available at:

<http://epc-co.com/epc/documents/gerber-files/EPC9041%20Development%20Board%20Gerbers.zip>

Assembly Resources at: <http://epc-co.com/epc/DesignSupport/AssemblyBasics.aspx>

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U.S. Patents 8,350,294; 8,404,508; 8,431,960; 8,436,398; 8,785,974; 8,890,168; 8,969,918; 8,853,749; 8,823,012

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